

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

Sheet 1 of 1

APPLICATION NO.

1514.1030
FIRST NAMED INVENTOR

JI Yong PARK et al.

FILING DATE

December 15, 2003

2815

U.S. PATENT DOCUMENTS

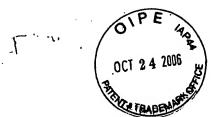
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FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	TRANSL YES	ATION NO	ABSTRACT
AG						
АН						
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)				
ma	AJ	Wang, Mingxiang and Man Wong. "Characterization of an Individual Grain Boundary in Metal-Induced Laterally Crystallized Polycrystalline Silicon Thin-Film Devices." <u>IEEE Transactions on Electron Devices.</u> Vol. 48, No. 8, August 2001, pages 1655-1660.		
M	AK	Cho, Hans S. et al. "Sequential Lateral Solidification of Ultra-Thin a-Si Films." Mat. Res. Soc. Symp. Proc. Vol. 621, 2001, pages 1-6.		

EXAMINER	DATE CONSIDERED			
Meutra C. Samber	1/30/07			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.				



Muther C. Panleus

Sheet 1 of 1 ATTORNEY DOCKET NO. **FORM PTO-1449** U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE 1514,1030 10/734,162 FIRST NAMED INVENTOR LIST OF REFERENCES CITED BY APPLICANT Ji Yong PARK et al. FILING DATE GROUP ART UNIT 2815 December 15, 2003 **U.S. PATENT DOCUMENTS** SUB-**FILING** DOCUMENT EXAMINER CLASS DATE INITIAL NO. DATE NAME CLASS AA AB AC AD **FOREIGN PATENT DOCUMENTS** DOCUMENT **ABSTRACT** NO. DATE COUNTRY **TRANSLATION** YES JP 9-8314 01/1997 **JAPAN** \mathbf{X} . ΑE MA AF KR 2001-71526 07/2001 REPUBLIC OF KOREA AG AH ΑI ΑJ **TRANSLATION** OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) YES NO Office Action issued in Korean Patent Application No. 2002-80326 on-November 22, 2004. M AL English Abstract issued in WIPO Publication No. 2000/002251. Χ DATE CONSIDERED **EXAMINER**

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